Maximum Ratings

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature ..... –65°C to +150°C

Ambient Temperature with Power Applied..... –55°C to +125°C

Supply Voltage to Ground Potential (Pin 28 to Pin 14) ..... –0.5V to +7.0V

DC Voltage Applied to Outputs in High-Z State[1] .....–0.5V to V_{CC} + 0.5V

DC Input Voltage[1] ..... –0.5V to V_{CC} + 0.5V

Output Current into Outputs (LOW)..... 20 mA

Static Discharge Voltage..... > 2001V (per MIL-STD-883, Method 3015)

Latch-up Current..... > 200 mA

Operating Range

Range	Ambient Temperature[2]	V_{CC}
Commercial	0°C to +70°C	5V ± 10%

Electrical Characteristics Over the Operating Range [3]

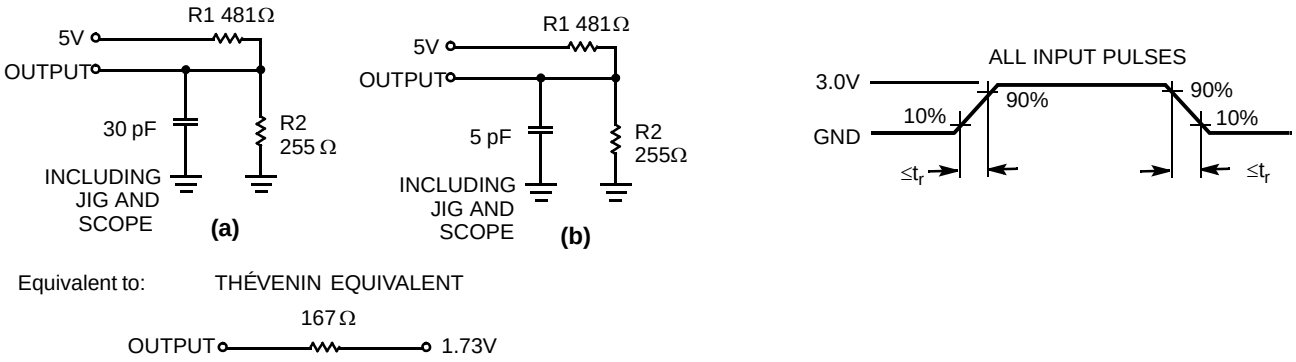
Parameter	Description	Test Conditions		-12		-15		-20		Unit
				Min.	Max.	Min.	Max.	Min.	Max.	
V_{OH}	Output HIGH Voltage	V_{CC} = Min., I_{OH}=–4.0 mA		2.4		2.4		2.4		V
V_{OL}	Output LOW Voltage	V_{CC} = Min., I_{OL}=8.0 mA			0.4		0.4		0.4	V
V_{IH}	Input HIGH Voltage			2.2	V_{CC} + 0.3V	2.2	V_{CC} + 0.3V	2.2	V_{CC} + 0.3V	V
V_{IL}	Input LOW Voltage			–0.5	0.8	–0.5	0.8	–0.5	0.8	V
I_{IX}	Input Leakage Current	GND ≤ V_I ≤ V_{CC}		–5	+5	–5	+5	–5	+5	µA
I_{OZ}	Output Leakage Current	GND ≤ V_O ≤ V_{CC}, Output Disabled		–5	+5	–5	+5	–5	+5	µA
I_{CC}	V_{CC} Operating Supply Current	V_{CC} = Max., I_{OUT} = 0 mA, f = f_{MAX} = $1/t_{RC}$	Com'l		160		155		150	mA
			L				90			mA
I_{SB1}	Automatic CE Power-down Current—TTL Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{IH}, V_{IN} ≥ V_{IH} or V_{IN} ≤ V_{IL}, f = f_{MAX}	Com'l		30		30		30	mA
			L				5			mA
I_{SB2}	Automatic CE Power-down Current—CMOS Inputs	Max. V_{CC}, $\overline{CE}$ ≥ V_{CC} – 0.3V V_{IN} ≥ V_{CC} – 0.3V or V_{IN} ≤ 0.3V, f = 0	Com'l		10		10		10	mA
			L				0.05			mA

Notes:
1. V_{IL} (min.) = –2.0V for pulse durations of less than 20 ns.
2. T_A is the "instant on" case temperature.
3. See the last page of this specification for Group A subgroup testing information.

Capacitance[4]

Parameter	Description	Test Conditions	Max.	Unit
C_{IN}	Input Capacitance	$T_A = 25°C$, f = 1 MHz, $V_{CC} = 5.0V$	8	pF
C_{OUT}	Output Capacitance		8	pF

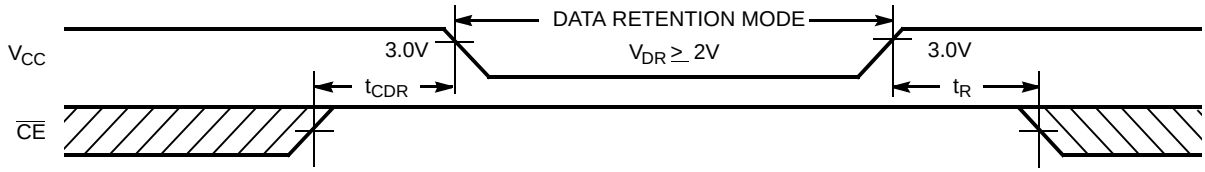
AC Test Loads and Waveforms[5]



Data Retention Characteristics Over the Operating Range (L-version only)

Parameter	Description	Conditions[6]	Min.	Max.	Unit
V_{DR}	V_{CC} for Data Retention		2.0		V
I_{CCDR}	Data Retention Current	$V_{CC} = V_{DR} = 2.0V$, $\overline{CE} \geq V_{CC} - 0.3V$, $V_{IN} \geq V_{CC} - 0.3V$ or $V_{IN} \leq 0.3V$		10	µA
t_{CDR}[4]	Chip Deselect to Data Retention Time		0		ns
t_R[5]	Operation Recovery Time		200		µs

Data Retention Waveform



Notes:
4. Tested initially and after any design or process changes that may affect these parameters.
5. $t_R \leq 3$ ns for the -12 and the -15 speeds. $t_R \leq 5$ ns for the -20 and slower speeds.
6. No input may exceed V_{CC} + 0.5V.

Switching Characteristics Over the Operating Range [3,7]

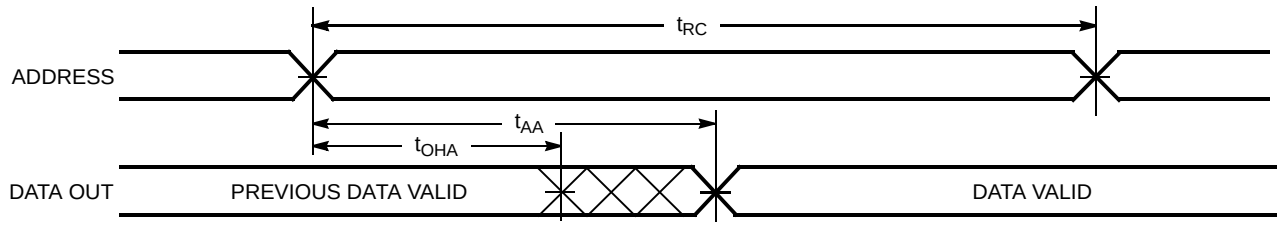
Parameter	Description	-12		-15		-20		Unit
		Min.	Max.	Min.	Max.	Min.	Max.	
Read Cycle								
t_{RC}	Read Cycle Time	12		15		20		ns
t_{AA}	Address to Data Valid		12		15		20	ns
t_{OHA}	Data Hold from Address Change	3		3		3		ns
t_{ACE}	$\overline{CE}$ LOW to Data Valid		12		15		20	ns
t_{DOE}	$\overline{OE}$ LOW to Data Valid		5		7		9	ns
t_{LZOE}	$\overline{OE}$ LOW to Low-Z[8]	0		0		0		ns
t_{HZOE}	$\overline{OE}$ HIGH to High-Z[8, 9]		5		7		9	ns
t_{LZCE}	$\overline{CE}$ LOW to Low-Z[8]	3		3		3		ns
t_{HZCE}	$\overline{CE}$ HIGH to High-Z[8, 9]		5		7		9	ns
t_{PU}	$\overline{CE}$ LOW to Power-up	0		0		0		ns
t_{PD}	$\overline{CE}$ HIGH to Power-down		12		15		20	ns
Write Cycle[10, 11]								
t_{WC}	Write Cycle Time	12		15		20		ns
t_{SCE}	$\overline{CE}$ LOW to Write End	9		10		15		ns
t_{AW}	Address Set-up to Write End	9		10		15		ns
t_{HA}	Address Hold from Write End	0		0		0		ns
t_{SA}	Address Set-up to Write Start	0		0		0		ns
t_{PWE}	$\overline{WE}$ Pulse Width	8		9		15		ns
t_{SD}	Data Set-up to Write End	8		9		10		ns
t_{HD}	Data Hold from Write End	0		0		0		ns
t_{HZWE}	$\overline{WE}$ LOW to High-Z[9]		7		7		10	ns
t_{LZWE}	$\overline{WE}$ HIGH to Low-Z[8]	3		3		3		ns

Notes:

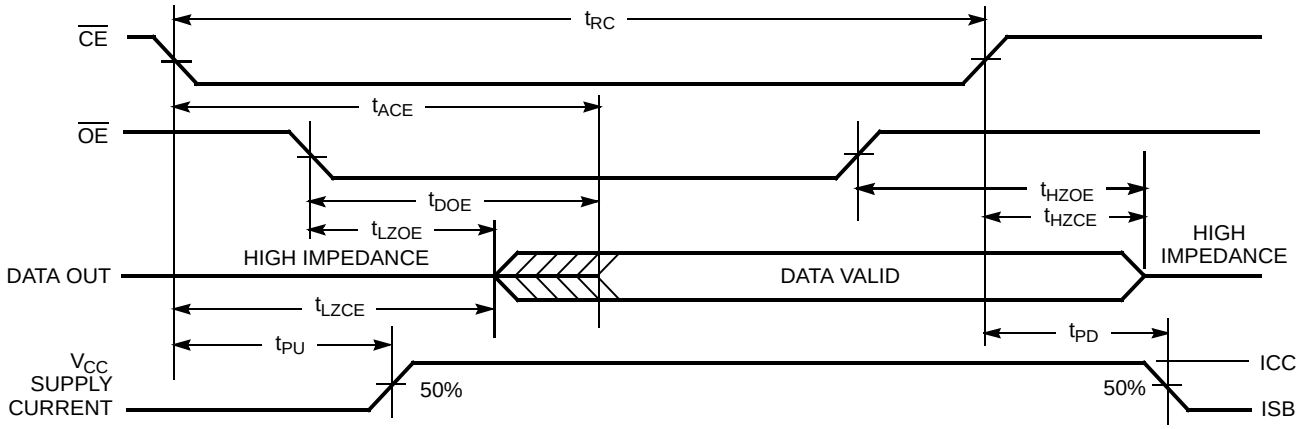
7. Test conditions assume signal transition time of 3 ns or less for -12 and -15 speeds and 5 ns or less for -20 and slower speeds, timing reference levels of 1.5V, input pulse levels of 0 to 3.0V, and output loading of the specified I_{OL}/I_{OH} and 30-pF load capacitance.
8. At any given temperature and voltage condition, t_{HZCE} is less than t_{LZCE}, t_{HZOE} is less than t_{LZOE}, and t_{HZWE} is less than t_{LZWE} for any given device.
9. t_{HZOE}, t_{HZCE}, and t_{HZWE} are specified with C_L = 5 pF as in part (b) of AC Test Loads. Transition is measured ±500 mV from steady-state voltage.
10. The internal write time of the memory is defined by the overlap of $\overline{CE}$ LOW and $\overline{WE}$ LOW. Both signals must be LOW to initiate a write and either signal can terminate a write by going HIGH. The data input set-up and hold timing should be referenced to the rising edge of the signal that terminates the write.
11. The minimum write cycle time for write cycle #3 ($\overline{WE}$ controlled, $\overline{OE}$ LOW) is the sum of t_{HZWE} and t_{SD}.

Switching Waveforms

Read Cycle No. 1[12, 13]



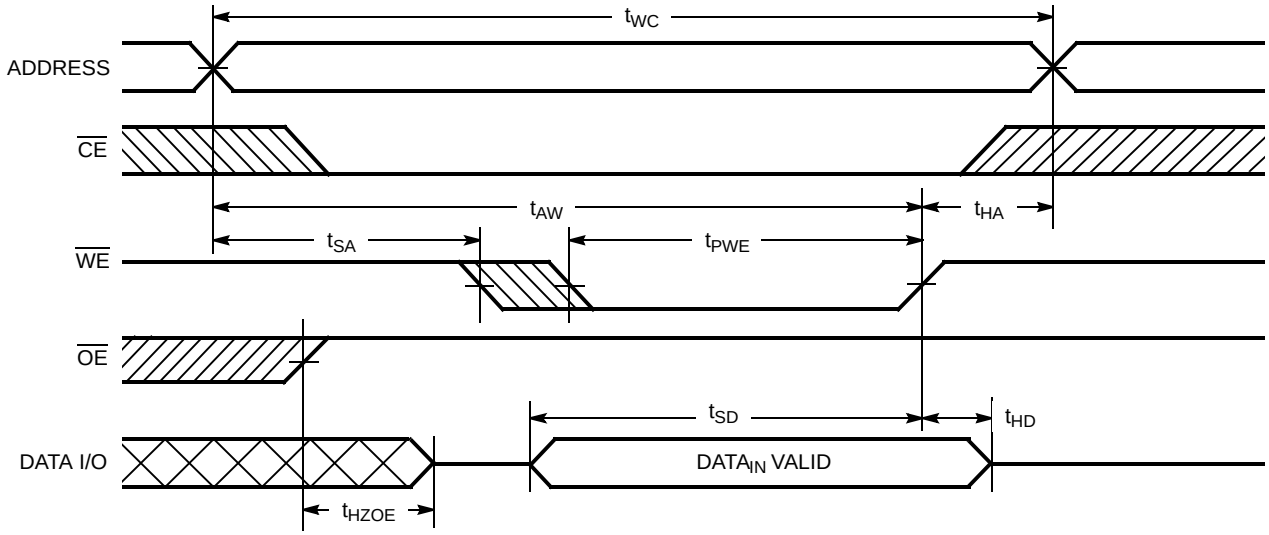
Read Cycle No. 2 [13, 14]



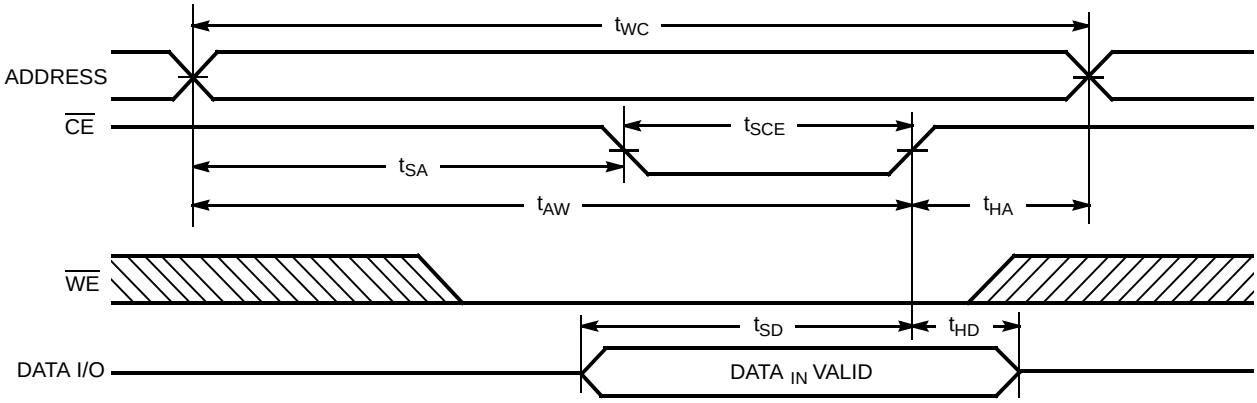
Notes:
12. Device is continuously selected. $\overline{OE}$, $\overline{CE}$ = V_{IL}.
13. $\overline{WE}$ is HIGH for read cycle.
14. Address valid prior to or coincident with $\overline{CE}$ transition LOW.

Switching Waveforms (continued)

Write Cycle No. 1 ($\overline{WE}$ Controlled)[10, 15, 16]



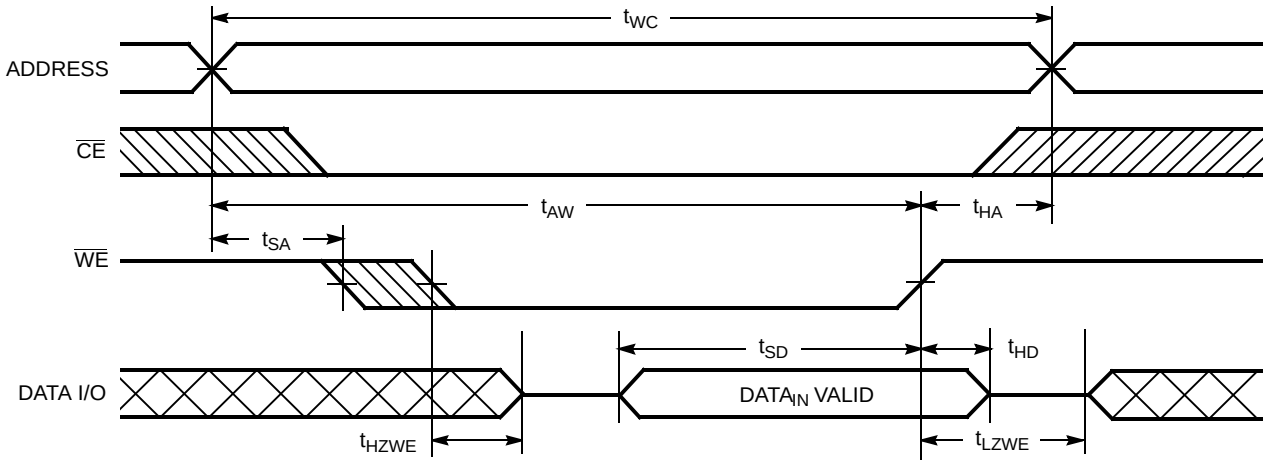
Write Cycle No. 2 ($\overline{CE}$ Controlled)[10, 15, 16]



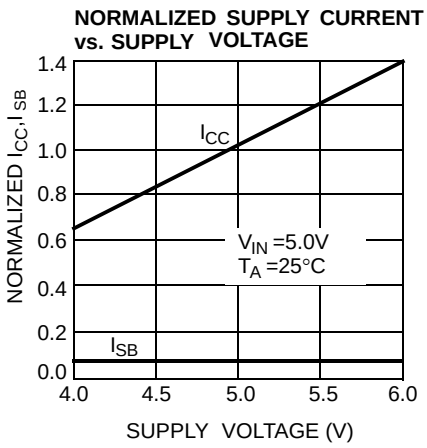
Notes:
15. Data I/O is high impedance if $\overline{OE} = V_{IH}$.
16. If $\overline{CE}$ goes HIGH simultaneously with $\overline{WE}$ HIGH, the output remains in a high-impedance state.

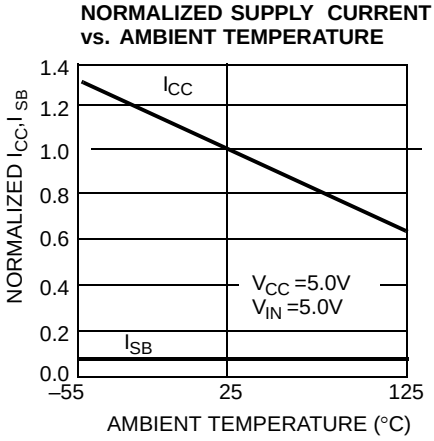
Switching Waveforms (continued)

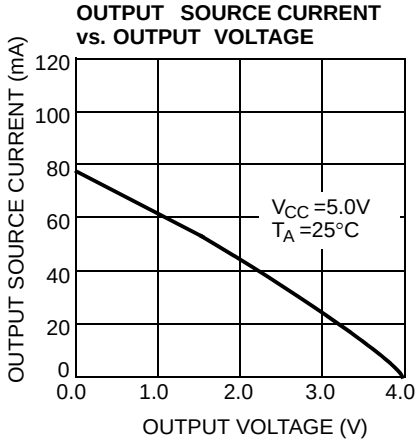
Write Cycle No. 3 ($\overline{WE}$ Controlled $\overline{OE}$ LOW)[11, 16]

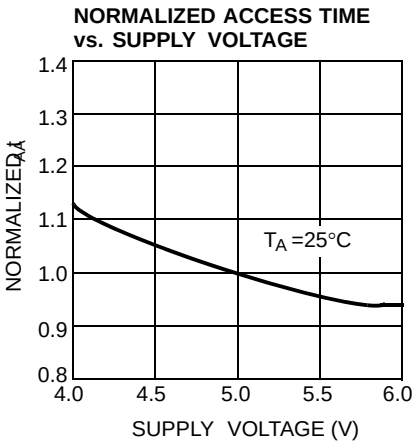


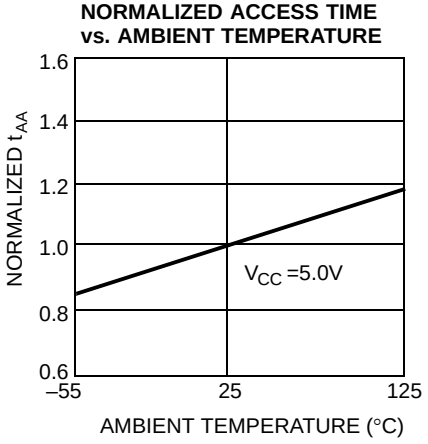
Typical DC and AC Characteristics

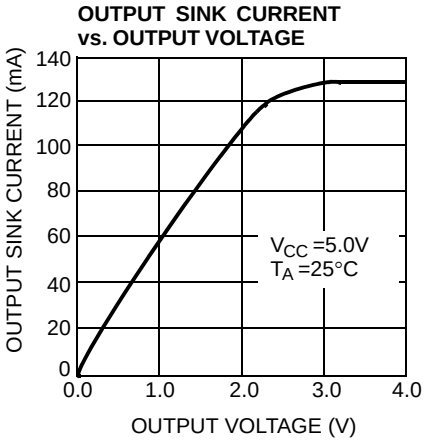




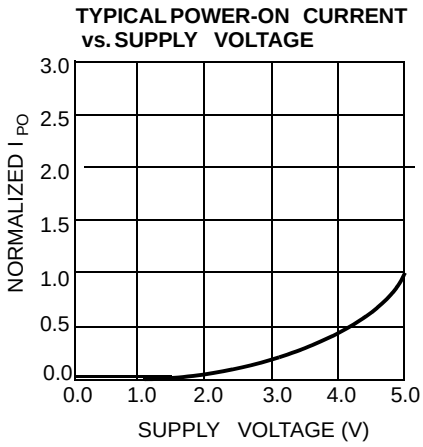


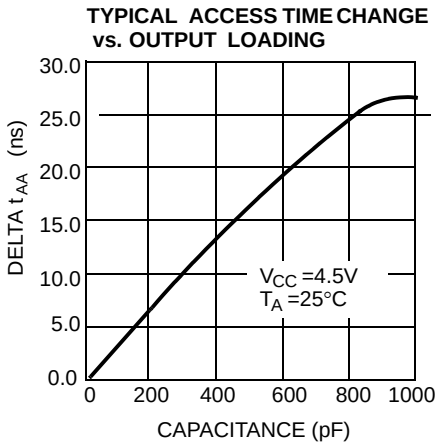


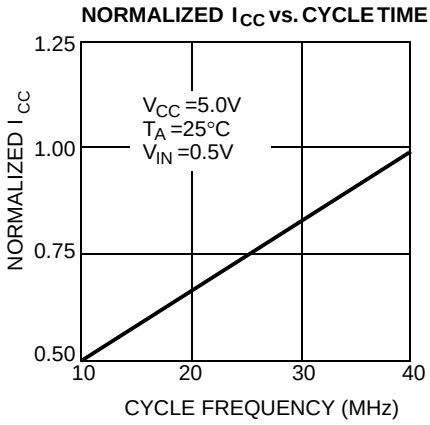




Typical DC and AC Characteristics (continued)







Truth Table

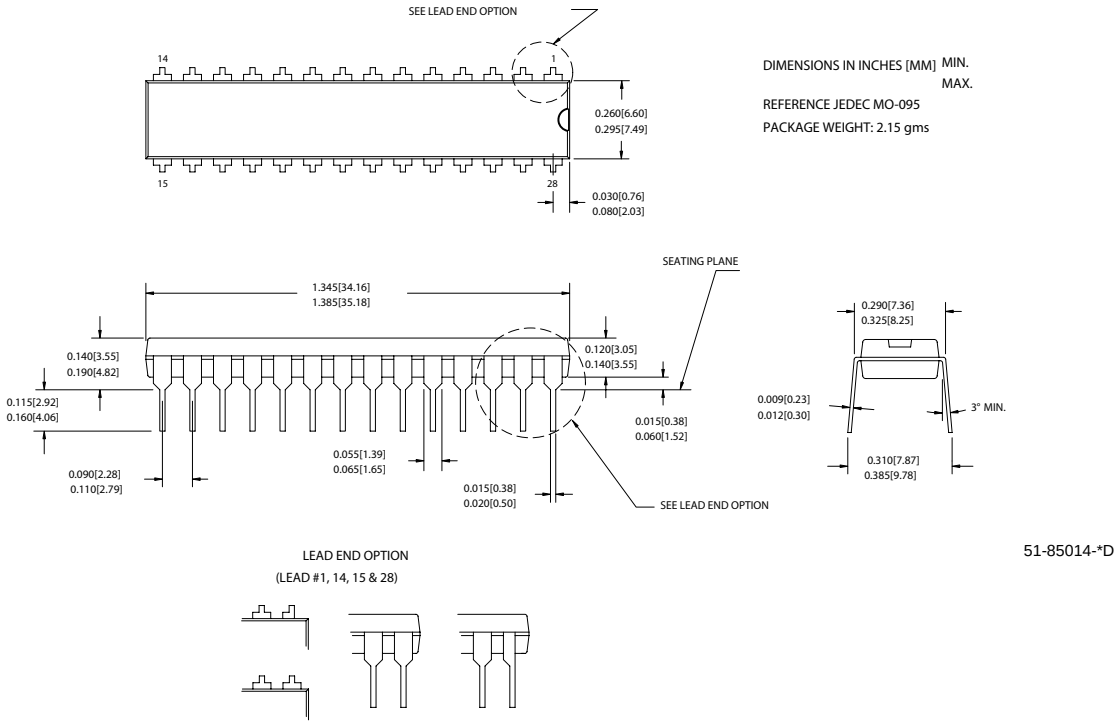
$\overline{CE}$	$\overline{WE}$	$\overline{OE}$	Inputs/Outputs	Mode	Power
H	X	X	High Z	Deselect/Power-down	Standby (I_{SB})
L	H	L	Data Out	Read	Active (I_{CC})
L	L	X	Data In	Write	Active (I_{CC})
L	H	H	High Z	Deselect, Output disabled	Active (I_{CC})

Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
12	CY7C199-12ZXC	51-85071	28-pin TSOP I (Pb-free)	Commercial
15	CY7C199-15ZXC	51-85071	28-pin TSOP I (Pb-free)	Commercial
	CY7C199L-15ZXC			
20	CY7C199-20PXC	51-85014	28-pin (300-Mil) Molded DIP (Pb-free)	Commercial

Package Diagrams

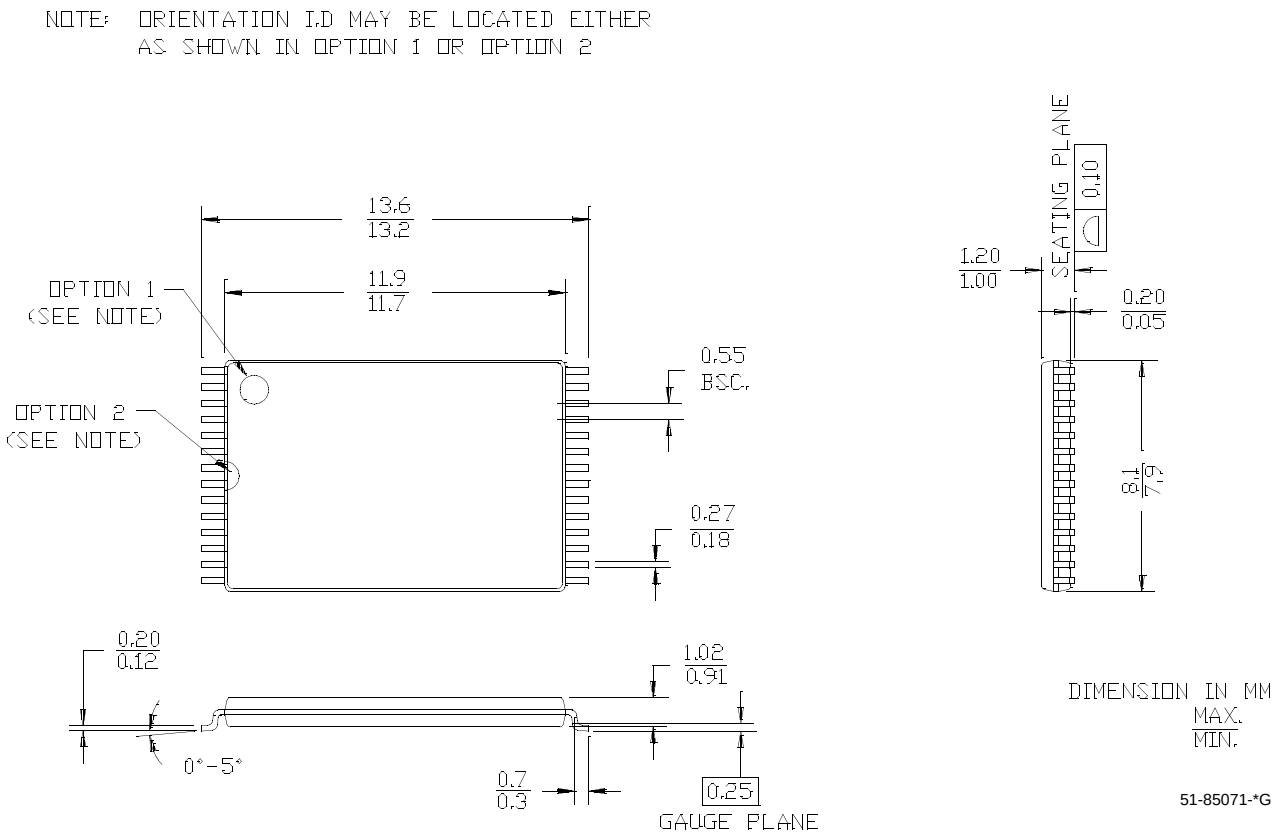
28-pin (300-Mil) PDIP (51-85014)



51-85014-*D

Package Diagrams (continued)

28-pin TSOP Type 1 (8x13.4 mm) (51-85071)



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Document History Page

Document Title: CY7C199 32K x 8 Static RAM Document Number: 38-05160				
REV.	**ECN NO.**	**Issue Date**	**Orig. of Change**	**Description of Change**
**	109971	10/28/01	SZV	Change from Spec number: 38-00239 to 38-05160
*A	121730	01/09/02	DFP	Updated Product Offering table
*B	492500	See ECN	NXR	Removed 8 ns, 10 ns, 25 ns , 35 ns, 45 ns speed bins Removed 28-Lead (300-Mil) CerDIP, 28-Pin Rectangular Leadless Chip Carrier, 28-Lead Molded SOIC, 28-Lead Molded SOJ packages from product offering Changed the description of I_{IX} from Input Load Current to Input Leakage Current in DC Electrical Characteristics table Removed I_{OS} parameter from DC Electrical Characteristics Table Updated Ordering Information Table